

Vanta[™] Element Handheld XRF Analyzer Affordable Alloy ID

Affordable, Rugged, and Connected

The Vanta Element handheld X-ray fluorescence (XRF) analyzer provides elemental analysis for alloy grade identification and sorting in as little as one second. Easy to operate, the Vanta Element analyzer's clear, fast grade ID and on-screen grade comparison help speed up metal testing for scrap sorting and metal manufacturing.

The analyzer's smartphone-like user interface helps increase efficiency and throughput with features like on-screen grade comparison, sorting instructions, and identifying contaminants or the presence of residual elements that can compromise value and quality. Easy to use and easy to learn, the software helps reduce user training and streamlines the sorting process.

Confidently Verify and Sort Metals and Alloys

The Vanta Element alloy database includes the most commonly used alloys in scrap recycling and manufacturing, but is easily customized for proprietary or additional grades.

- Non-ferrous alloys
- Low-alloy steels

- Copper alloys
- Nickel and high-temp alloys
- Precious metals
- Aluminum alloys



Modern

The Vanta[™] Element analyzer includes connectivity features to help streamline your quality control process.

Powerful Processing

- Vanta electronics
- Axon Technology[™] stability and count rate

Convenient Data Management

- Wireless data transfer to a network folder (optional)
- Cloud data storage and real-time remote data viewing using the Olympus Scientific Cloud™
- Direct export to a USB drive
- 1 GB microSD[™] card for storing results

Global Support

We are committed to providing the best technical support and after-sales service for our products, applications, training, and technologies through our global network of sales and customer service teams.

Rugged and Affordable

Built for harsh and demanding environments, the Vanta Element analyzer delivers a lower cost of ownership:

- IP54 rated for protection against dust and moisture
- Drop tested (MIL-STD-810G) to protect against falls and reduce the need for costly repairs
- Rated for continuous testing from -10 °C to 45 °C (14 °F to 113 °F)
- Stainless-steel faceplate for wear protection
- Tough, thick (50 μm) Kapton[®] window protects the analyzer
- Easy, toolless window replacement





Clear, graphic on-screen grade comparison.

OLYMPUS SCIENTIFIC SOLUTIONS AMERICAS is certified to ISO 9001, ISO 14001, and OHSAS 18001.

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